Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,896	CHEN ET AL.	
Examiner	Art Unit	
Stephen W. Smoot	2813	

	SEARCHED				
Class	Subclass	Date	Examiner		
438	108	1/27/2005	sws		
438	612	1/27/2005	sws		
438	613	1/27/2005	sws		
438	614	1/27/2005	sws		
257	738	1/27/2005	sws		
257	E21.508	1/27/2005	sws		
29	842	1/27/2005	sws		
		-			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
			-		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Key Words: Solder Ball, Bump - Flux; Active Surface; Bond Pad; Under Bump Metallurgy;	1/27/2005	LU.S sws
Passivation Layer; Solder Reflow; Solid Flux.	1/27/2005	L.W.S sws
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Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	1/27/2005	I.U.S.